

Notice of References Cited	Application/Control No. 10/816,416		Applicant(s)/Patent Under Reexamination OKABE ET AL.	
	Examiner JONATHAN R. BECKLEY		Art Unit 2625	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,115,132 A	09-2000	Nakatsuma et al.	358/1.14
*	B	US-6,385,728 B1	05-2002	DeBry, Roger K.	726/9
*	C	US-6,477,580 B1	11-2002	Bowman-Amuah, Michel K.	709/231
*	D	US-6,539,396 B1	03-2003	Bowman-Amuah, Michel K.	707/103R
*	E	US-2003/0093675 A1	05-2003	Hibino et al.	713/168
*	F	US-6,578,068 B1	06-2003	Bowman-Amuah, Michel K.	709/203
*	G	US-6,615,253 B1	09-2003	Bowman-Amuah, Michel K.	709/219
*	H	US-6,775,023 B1	08-2004	Fukunaga et al.	358/1.15
*	I	US-6,980,668 B1	12-2005	Naito et al.	382/100
*	J	US-7,170,620 B2	01-2007	Gassho et al.	358/1.15
*	K	US-7,373,409 B2	05-2008	Miyake et al.	709/229
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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